

Application/Control No.	Applicant(s)/Patent unde Reexamination	r
09/936,624	LEAR ET AL.	
Examiner	Art Unit	
Mark A. Mais	2619	

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Class	Subclass	Date	Examiner
370	254 255	5/2/2007	МАМ
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	389 390		
	396 398		
	395.31 400		
	406 408		
	422 428		
SAME AS	ABOVE	11/30/2007	MAM
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INT	ERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
See Inventorship Search	5/2/2007	MAM		
See Attached Electronic Search	5/2/2007	MAM		
See Attached Electronic Search [updated]	11/30/2007	МАМ		
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